

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S1	74	Hirabayashi-Osamu.in.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/27 16:59
S2	33064	ECC (error adj correction adj code)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/27 19:25
S3	12	S1 and S2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 11:37
S4	17013	(error fault flaw miss) same (number plurality multitude numerous abundant several) same (exceed surpass beyond overcome overwhelm surpass) same (system test device circuit chip)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 11:53
S5	630	S4 and S2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 11:54
S6	1353	(error fault flaw miss) with (number plurality multitude numerous abundant several) with (exceed surpass beyond overcome overwhelm surpass) with (system test device circuit chip)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 11:54
S7	156	S6 and S2	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 11:54
S8	25076413	@ad<="20040116"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 11:55

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S9	145	S7 and S8	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 15:38
S10	33064	ECC (error adj correction adj code)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 18:00
S11	1353	(error fault flaw miss) with (number plurality multitude numerous abundant several) with (exceed surpass beyond overcome overwhelm surpass) with (system test device circuit chip)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 15:41
S12	156	S11 and S10	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 15:41
S13	25076413	@ad<="20040116"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 15:41
S14	145	S12 and S13	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 15:41
S15	4	S14 and (BIST (built adj in adj circuit adj test) (built adj in adj self adj test))	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 16:23
S16	137	(ECC (error adj correction adj code)) and (BIST (built adj in adj circuit adj test) (built adj in adj self adj test)) and S13	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 17:44

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S17	133	S16 not S14	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 17:24
S18	2	"4680760".pn.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 17:24
S19	4044	(check\$3 test\$4 validat\$4 verif\$8 examin\$7 confirm\$4 establish\$4 prov\$4) near5 (ECC (error adj correction adj code)) and S13	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 17:53
S20	0	((check\$3 test\$4 validat\$4 verif\$8 examin\$7 confirm\$4 establish\$4 prov\$4) near5 (ECC (error adj correction adj code)) and S13).ab.	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 17:54
S21	5222	((check\$3 test\$4 validat\$4 verif\$8 examin\$7 confirm\$4 establish\$4 prov\$4) with (ECC (error adj correction adj code)) and S13)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 17:55
S22	899	((check\$3 test\$4 validat\$4 verif\$8 examin\$7 confirm\$4 establish\$4 prov\$4) with ((ECC (error adj correction adj code)) near3 (circuit chip wafer IC (integrated adj circuit)))) and S13	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 18:04
S23	459	((check\$3 test\$4 validat\$4 verif\$8 examin\$7 confirm\$4 establish\$4 prov\$4) with ((ECC (error adj correction adj code)) adj (circuit chip wafer IC (integrated adj circuit)))) and S13	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 18:05
S24	439	S23 not (S16 S14)	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/24 18:06

## EAST Search History

S25	2	2004-009329	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/27 17:06
S26	44371	((SED SEC (single adj error adj ((correction correcting) (detection detecting)))) and (SED SEC (single adj error adj ((correction correcting) (detection detecting)))) same exceed	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/27 17:28
S34	15	(SEc and DED) same exceed	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/27 17:21
S35	50	((SEC SED) and (DED DEC)) same exceed	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/27 19:34
S36	35	S35 not S34	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/27 19:14
S37	8	("4701909"   "4965883"   "5432800"   "5892464"   "5996110"   "6084535"   "6170073"   "6473877").PN. OR ("6910169").URPN.	US-PGPUB; USPAT; USOCR	OR	ON	2006/02/27 19:27
S38	116	((SEC DEC) same exceed) and (ECC (error adj correction adj code))	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/02/27 19:35
S39	106	S38 not S35	US-PGPUB; USPAT; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/01 14:11
S40	164	uncorrectable with (error adj flag)	USPAT	OR	ON	2006/03/02 10:56
S41	10420	(statuse step) with (indicate indicated indicating indicates) with flag	USPAT	OR	ON	2006/03/02 11:06

## EAST Search History

S42	25080792	@ad<="20040116"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 11:01
S44	33129387	@pd<="20040116"	US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM_TDB	OR	ON	2006/03/02 11:01
S45	9123	S41 and S44	USPAT	OR	ON	2006/03/02 11:02
S46	4931	(statuse operation) with (indicate indicated indicating indicates) with flag	USPAT	OR	ON	2006/03/02 11:07
S47	4312	S46 and S44	USPAT	OR	ON	2006/03/02 11:08